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List of Documents

Cited by Applicant

(Use several sheets if necessary)

Applicant: William A. CHREN, Jr.

Filing Date: September 6, 2000

Group: 2787

U.S. PATENT DOCUMENTS

Ex'rs In'l		Document Number	Date	Name	Class	Sub- class	Filing Date, if applicable
A.W.	AA1	5,892,632	April 6, 1999	Behrens et al.			

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FOREIGN PATENT DOCUMENTS

		Document Number	Date	Country	Class	Sub- class	Trans'l'n Yes/No

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)

A.W.	AA2	Chren, W.A. Jr., "One-Hot Residue Coding for Low Delay-Power Product CMOS Design", IEEE Transactions on Circuits and Systems II: Analog and Digital Signal Processing, v. 45. no. 3, March 1998, pgs. 303-313.					
A.W.	AA3	Karim Arabi et al., "Oscillation Built-In Self-Test (OBIST) Scheme for Functional and Structural Testing of Analog and Mixed-Signal Integrated Circuits", Proceedings of the IEEE International Test Conference, Washington, D.C., 1997, pp. 786-795.					
A.W.	AA4	N. S. Szabo, et al., "Residue Arithmetic and its Applications to Computer Technology, McGraw-Hill, 1967, pgs. 147-150.					
A.W.	AA5	Chren, W.A. Jr., "A New Residue Number System Division Algorithm", Computers and Mathematics with Applications, vol. 19, no. 7, 1990, pgs. 13-29, 1990.					

Examiner:

aw

Date Considered:

6-15-03

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.